N-channel TrenchMOS standard level FET

Rev. 02 — 9 January 2008

Product data sheet

1. Product profile

1.1 General description

N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using NXP General-Purpose Automotive (GPA) TrenchMOS technology specifically optimized for linear operation. This product has been designed and qualified to the appropriate AEC standard for use in automotive critical applications.

1.2 Features

- 175 °C rated
- Stable operation in linear mode
- Q101 compliant
- TrenchMOS technology

1.3 Applications

- 12 V and 24 V loads
- DC linear motor control
- Automotive systems
- Repetitive clamped inductive switching

1.4 Quick reference data

Table 1. Quick reference

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
I_D	drain current	$V_{GS} = 10 \text{ V}; T_{mb} = 25 ^{\circ}\text{C};$ see Figure 4 and 1	[1]	-	-	75	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>		-	-	300	W
Avalanch	e ruggedness						
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	$\begin{split} I_D = 75 \text{ A; } V_{sup} &\leq 55 \text{ V;} \\ R_{GS} = 50 \Omega; V_{GS} = 10 \text{ V;} \\ T_{j(\text{init})} &= 25 ^{\circ}\text{C; } \text{ unclamped} \\ \text{inductive load} \end{split}$		-	-	1.1	J
Static cha	aracteristics						
R _{DSon}	drain-source on-state resistance	V_{GS} = 10 V; I_D = 25 A; T_j = 25 °C; see <u>Figure 12</u> and <u>13</u>		-	8.5	10	mΩ

^[1] Continuous current is limited by package.



2. Pinning information

Table 2. Pinning

	_			
Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate	mb	D
2	D	drain		
3	S	source		G (FX)
mb	D	mounting base; connected to drain	SOT404 (D2PAK)	mbb076 S

3. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
BUK7610-55AL	D2PAK	plastic single-ended surface-mounted package (D2PAK); 3 leads (one lead cropped)	SOT404

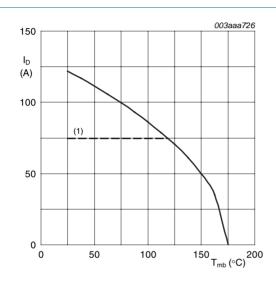
4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DS}	drain-source voltage	$T_j \ge 25 \text{ °C}; T_j \le 175 \text{ °C}$	-	55	V
V_{DGR}	drain-gate voltage	$R_{GS} = 20 \text{ k}\Omega$	-	55	V
V_{GS}	gate-source voltage		-20	20	V
I _D	drain current	T_{mb} = 25 °C; V_{GS} = 10 V; see <u>Figure 4</u> and <u>1</u>	[1][2]	122	Α
		T_{mb} = 25 °C; V_{GS} = 10 V; see <u>Figure 4</u> and <u>1</u>	[3]	75	Α
		T_{mb} = 100 °C; V_{GS} = 10 V; see <u>Figure 4</u>	[3]	75	Α
I _{DM}	peak drain current	T_{mb} = 25 °C; $t_p \le 10 \mu s$; pulsed	-	490	А
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	300	W
T _{stg}	storage temperature		-55	175	°C
Tj	junction temperature		-55	175	°C
Avalanci	ne ruggedness				
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	I_D = 75 A; V_{sup} \leq 55 V; R_{GS} = 50 $\Omega;$ V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; unclamped inductive load	-	1.1	J
E _{DS(AL)R}	repetitive drain-source avalanche energy	see <u>Figure 3</u>	[4][5] <u> </u>	-	J
Source-c	drain diode				
Is	source current	T _{mb} = 25 °C	[1][2]	122	Α
		T _{mb} = 25 °C	[3] _	75	Α
I _{SM}	peak source current	$t_p \leq$ 10 μ s; pulsed; T_{mb} = 25 $^{\circ}$ C	-	490	Α
BUK7610-55AL_:	2			© NXP B.V	. 2008. All rights res

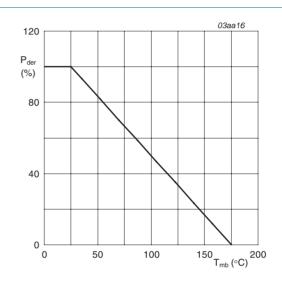
- [1] Current is limited by power dissipation chip rating.
- [2] Refer to document 9397 750 12572 for further information.
- [3] Continuous current is limited by package.
- [4] Single shot avalanche rating limited by maximum junction temperature of 175 °C.
- [5] Repetitive avalanche rating limited by average junction temperature of 170 °C.
- [6] Refer to application note AN10273 for further information.



 $V_{GS} \ge 10 V$

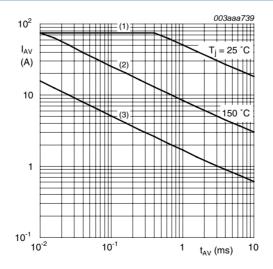
(1) Capped at 75 A due to package.

Fig 1. Continuous drain current as a function of mounting base temperature



$$P_{der} = \frac{P_{tot}}{P_{tot(25^{\circ}C)}} \times 100 \%$$

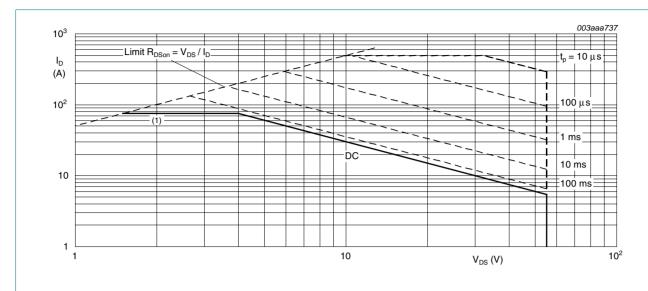
Fig 2. Normalized total power dissipation as a function of mounting base temperature



- (1) Single-shot.
- (2) Single-shot.
- (3) Repetitive.

Fig 3. Single-shot and repetitive avalanche rating; avalanche current as a function of avalanche period

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 T_{mb} = 25 °C; I_{DM} is single pulse

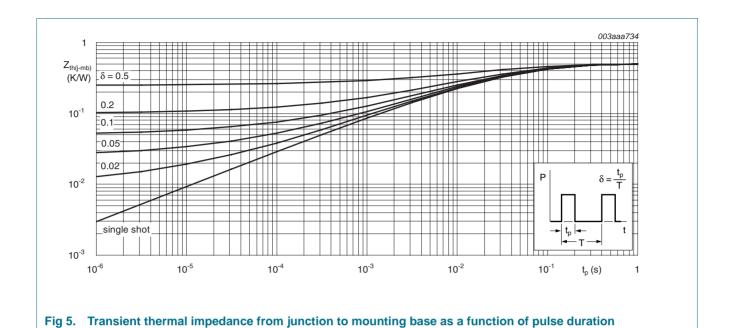
(1) Capped at 75 A due to package.

Fig 4. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-a)}$	thermal resistance from junction to ambient	mounted on a printed-circuit board; minimum footprint; vertical in still air	-	50	-	K/W
R _{th(j-mb)}	thermal resistance from junction to mounting base	see Figure 5	-	0.25	0.5	K/W



6. Characteristics

Table 6. Characteristics

Table 0.	Characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	Static characteristics					
$V_{(BR)DSS}$	drain-source breakdown voltage	$I_D = 250 \mu A; V_{GS} = 0 V;$ $T_j = -55 °C$	50	-	-	V
		$I_D = 250 \mu A; V_{GS} = 0 V;$ $T_j = 25 °C$	55	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	I_D = 1 mA; V_{DS} = V_{GS} ; T_j = 25 °C; see <u>Figure 10</u> and <u>11</u>	2	3	4	V
		I_D = 1 mA; V_{DS} = V_{GS} ; T_j = 175 °C; see <u>Figure 10</u> and <u>11</u>	1	-	-	V
		$I_D = 1$ mA; $V_{DS} = V_{GS}$; $T_j = -55$ °C; see <u>Figure 10</u> and <u>11</u>	-	-	4.4	V
I _{DSS}	drain leakage current	$V_{DS} = 55 \text{ V}; V_{GS} = 0 \text{ V};$ $T_j = 175 \text{ °C}$	-	-	500	μΑ
		V_{DS} = 55 V; V_{GS} = 0 V; T_j = 25 °C	-	0.05	10	μΑ
I_{GSS}	gate leakage current	$V_{DS} = 0 \text{ V}; V_{GS} = +20 \text{ V};$ $T_j = 25 \text{ °C}$	-	2	100	nA
		$V_{DS} = 0 \text{ V}; V_{GS} = -20 \text{ V};$ $T_j = 25 \text{ °C}$	-	2	100	nA
R _{DSon}	drain-source on-state resistance	$V_{GS} = 10 \text{ V; } I_D = 25 \text{ A;}$ $T_j = 175 \text{ °C; see } \frac{\text{Figure 12}}{13} \text{ and}$	-	-	20	mΩ
		$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A}; T_j = 25 ^{\circ}\text{C};$ see Figure 12 and 13	-	8.5	10	mΩ

Table 6. Characteristics ... continued

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Source-d	rain diode					
V_{SD}	source-drain voltage	$I_S = 25 \text{ A}$; $V_{GS} = 0 \text{ V}$; $T_j = 25 \text{ °C}$; see Figure 16	-	0.85	1.2	V
t _{rr}	reverse recovery time	$I_S = 20 \text{ A}; dI_S/dt = -100 \text{ A/}\mu\text{s};$ $V_{GS} = 0 \text{ V}; V_{DS} = 30 \text{ V}; T_j = 25 ^{\circ}\text{C}$	-	73	-	ns
Q _r	recovered charge	$I_S = 20 \text{ A}; dI_S/dt = -100 \text{ A/}\mu\text{s};$ $V_{GS} = 0 \text{ V}; V_{DS} = 30 \text{ V}; T_j = 25 ^{\circ}\text{C}$	-	430	-	nC
Dynamic	characteristics					
Q _{G(tot)}	total gate charge	$I_D = 25 \text{ A}; V_{DS} = 44 \text{ V};$ $V_{GS} = 10 \text{ V}; T_j = 25 ^{\circ}\text{C};$ see Figure 14	-	124	-	nC
Q_{GS}	gate-source charge	$I_D = 25 \text{ A}; V_{DS} = 44 \text{ V};$ $V_{GS} = 10 \text{ V}; T_j = 25 ^{\circ}\text{C};$ see Figure 14	-	22	-	nC
Q_{GD}	gate-drain charge	$I_D = 25 \text{ A}; V_{DS} = 44 \text{ V};$ $V_{GS} = 10 \text{ V}; T_j = 25 ^{\circ}\text{C};$ see Figure 14	-	50	-	nC
$V_{GS(pl)}$	gate-source plateau voltage	$I_D = 25 \text{ A}; V_{DS} = 44 \text{ V}; T_j = 25 \text{ °C};$ see <u>Figure 14</u>	-	5	-	V
C _{iss}	input capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V};$ $f = 1 \text{ MHz}; T_j = 25 ^{\circ}\text{C};$ $see \frac{\text{Figure 15}}{}$	-	4710	6280	pF
C _{oss}	output capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V};$ $f = 1 \text{ MHz}; T_j = 25 ^{\circ}\text{C};$ $\text{see } \frac{\text{Figure } 15}{\text{ C}}$	-	980	1180	pF
C _{rss}	reverse transfer capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V};$ $f = 1 \text{ MHz}; T_j = 25 ^{\circ}\text{C};$ see Figure 15	-	560	770	pF
t _{d(on)}	turn-on delay time	$V_{DS} = 30 \text{ V; } R_{L} = 1.2 \Omega;$ $V_{GS} = 10 \text{ V; } R_{G(ext)} = 10 \Omega;$ $T_{j} = 25 \text{ °C}$	-	33	-	ns
t _r	rise time	$V_{DS} = 30 \text{ V}; R_L = 1.2 \Omega;$ $V_{GS} = 10 \text{ V}; R_{G(ext)} = 10 \Omega;$ $T_j = 25 \text{ °C}$	-	117	-	ns
t _{d(off)}	turn-off delay time	$V_{DS} = 30 \text{ V; } R_L = 1.2 \Omega;$ $V_{GS} = 10 \text{ V; } R_{G(ext)} = 10 \Omega;$ $T_j = 25 \text{ °C}$	-	132	-	ns
t _f	fall time	$V_{DS} = 30 \text{ V; } R_L = 1.2 \Omega;$ $V_{GS} = 10 \text{ V; } R_{G(ext)} = 10 \Omega;$ $T_j = 25 \text{ °C}$	-	95	-	ns
L _D	internal drain inductance	from upper edge of drain mounting base to center of die; $T_j = 25 ^{\circ}\text{C}$	-	2.5	-	nΗ
L _S	internal source inductance	from source lead to source bond pad; T _i = 25 °C	-	7.5	-	nΗ

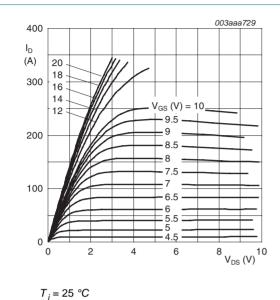
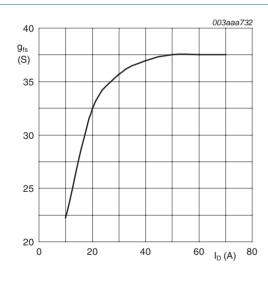


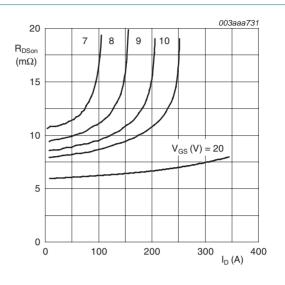
Fig 6. Output characteristics: drain current as a function of drain-source voltage; typical values



drain current; typical values

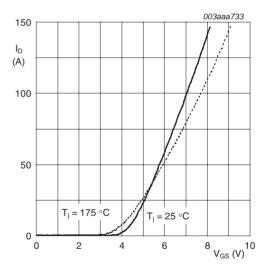
Fig 8. Forward transconductance as a function of

 $T_i = 25 \text{ °C}; V_{DS} = 25 \text{ V}$



T_i = 25 °C

Fig 7. Drain-source on-state resistance as a function of drain current; typical values



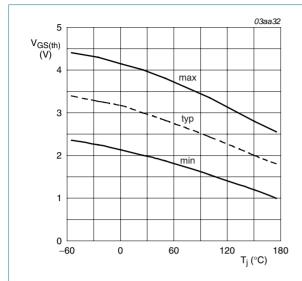
 $V_{DS} = 25 V$

Fig 9. Transfer characteristics: drain current as a function of gate-source voltage; typical values

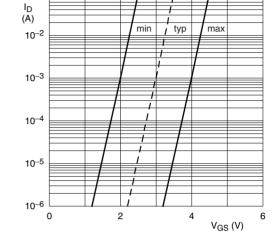
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$$I_D = 1 mA; V_{DS} = V_{GS}$$

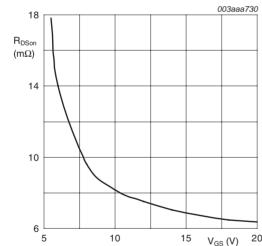


$$T_j = 25 \, ^{\circ}C; V_{DS} = V_{GS}$$

 10^{-1}

Fig 10. Gate-source threshold voltage as a function of

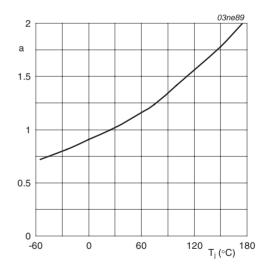




$$T_i = 25 \text{ °C}; I_D = 25 \text{ A}$$

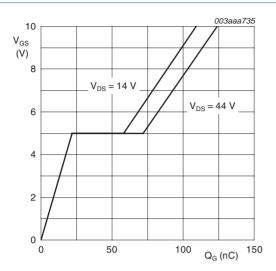
Fig 12. Drain-source on-state resistance as a function of gate-source voltage; typical values





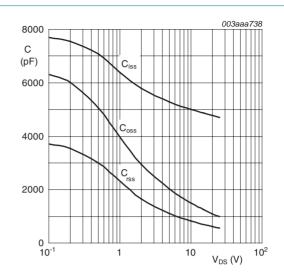
$$a = \frac{R_{DSon}}{R_{DSon(25^{\circ}C)}}$$

Fig 13. Normalized drain-source on-state resistance factor as a function of junction temperature



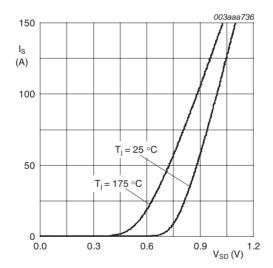
$$T_i = 25 \text{ °C}; I_D = 25 \text{ A}$$

Fig 14. Gate-source voltage as a function of gate charge; typical values



 $V_{GS} = 0 V$; f = 1 MHz

Fig 15. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values



 $V_{GS} = 0 V$

Fig 16. Source current as a function of source-drain voltage; typical values

7. Package outline

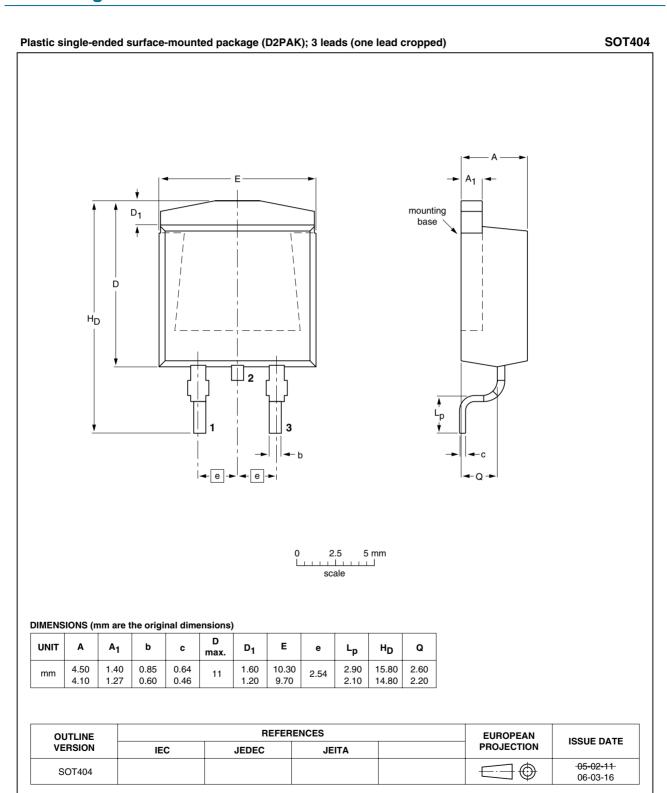


Fig 17. Package outline SOT404 (D2PAK)

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8. Revision history

Table 7. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes	
BUK7610-55AL_2	20080109	Product data sheet	-	BUK75_7610_55AL_1	
Modifications:		mat of this data sheet has been redesigned to comply with the new identitynes of NXP Semiconductors.			
	 Legal texts 	have been adapted to the	new company name whe	ere appropriate.	
	 Typical ther 	mal resistance (j-mb) figur	e added in <u>Table 5</u> .		
BUK75_7610_55AL_1	20041022	Product data sheet	-	-	

9. Legal information

9.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
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